

Day : Friday
 Date: 10/7/2005

Time: 14:00:10

PALM INTRANET**Inventor Name Search Result**

Your Search was:

Last Name = SEKINO

First Name = TAKASHI

Application#	Patent#	Status	Date Filed	Title	Inventor Name
<u>07768587</u>	<u>5225775</u>	150	09/30/1991	IC TESTING DEVICE FOR PERMITTING ADJUSTMENT OF TIMING OF A TEST SIGNAL	SEKINO, TAKASHI
<u>08641064</u>	<u>5869992</u>	150	04/29/1996	DELAY TIME CONTROL CIRCUIT	SEKINO, TAKASHI
<u>08838429</u>	<u>5821529</u>	150	04/07/1997	MEASURING BOARD HAVING AN OPTICALLY DRIVEN SWITCH AND I/O TERMINAL TESTING SYSTEM USING THE SAME	SEKINO, TAKASHI
<u>09254894</u>	<u>6462598</u>	150	06/08/2001	DELAY TIME CONTROL CIRCUIT	SEKINO, TAKASHI
<u>09323228</u>	<u>6276772</u>	150	06/01/1999	INK JET PRINTER USING PIEZOELECTRIC ELEMENTS WITH IMPROVED INK DROPLET IMPINGING ACCURACY	SEKINO, TAKASHI
<u>09584749</u>	<u>6678478</u>	150	06/01/2000	CORRECTING METHOD OF OPTICAL SIGNAL TRANSMISSION SYSTEM AND OPTICAL SIGNAL TRANSMISSION SYSTEM USING SAID CORRECTING METHOD	SEKINO, TAKASHI
<u>09588615</u>	<u>6294949</u>	150	06/06/2000	Voltage drive circuit, voltage drive apparatus and semiconductor-device testing apparatus	SEKINO, TAKASHI
<u>10303915</u>	<u>6749279</u>	150	11/26/2002	INKJET RECORDING DEVICE CAPABLE OF CONTROLLING EJECTION TIMING OF EACH NOZZLE INDIVIDUALLY	SEKINO, TAKASHI
<u>10757304</u>	Not	30	01/14/2004	Input-output circuit and a testing	SEKINO, TAKASHI

	Issued			apparatus	
<u>11094325</u>	Not Issued	30	03/30/2005	Test device and setting method	SEKINO, TAKASHI
<u>11101157</u>	Not Issued	30	04/07/2005	High frequency delay circuit and test apparatus	SEKINO, TAKASHI
<u>11202391</u>	Not Issued	19	08/11/2005	Differential comparator circuit test head, and test apparatus	SEKINO, TAKASHI

Inventor Search Completed: No Records to Display.

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